Form PTO 1449		U.S. DEPAR	RTMENT OF	ATTY DOCKET NO.	SERIAL	NO.			
OMMERCE (Modified)		PATENT A	ND TRADEMARK	277605US6YA PCT	10/550,215				
FFICE				APPLICANT OF E					
LIST OF RE	FEREN	ICES CITED BY	APPLICANT	Gary ESCHER, et al.					
				FILING DATE	GROUP				
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATIO				
VY			44040004	Europe (in English)	YES	NO			
	<u> </u>	1 156 130	01/06/1998	Europe (in English)  Japan (w/ English abstract and computer translation)	×				
	AB	10-004083		Japan (w/ English abstract; corresponding to US 2001/0003271 A1)	+	×			
	AC	2001-226773	08/21/2001	Japan (w/ English abstract; corresponding to US 2003/0010446 A1)	+				
	AD	2000-303180	10/31/2000		<del>  </del>				
	AE	0 814 495	06/1997	Europe (in English)	<del>  _  </del>				
	AF	05-198532	08/1993	Japan (w/ English abstract and computer translation)	×				
	AG	10-214819	08/1998	Japan (w/ English abstract and computer translation)	×	×			
	AH 2002-151473 05/2002 Japan (w/ English abstract; corresponding to US 2004/0035364 A1)								
	Al	02/39495	05/16/2002	WIPO (w/ English abstract; corresponding to US 2004/0035364 A1)	┿	×			
	LA	1 069 603	01/17/2001	Europe (In English)	ļ				
	AK	07-245295	09/1995	Japan (w/ English abstract and computer translation)	×				
	AL	0 841 838 05/1998 Europe (in English)							
	AM	99/50886	10/1999	WIPO (in English)					
	AN	0 573 057	12/1993	Europe (in English)					
	AO	2000-124197	04/28/2000	Japan (w/ English abstract and computer translation)	×				
	AP	1 081 749	07/03/2001	Europe (in English)					
	AQ	4-238882	08/1992	Japan (w/ certified English translation)	×				
	AR	1-312087	12/1989	Japan (w/ English abstract; corresponding to US Patent 4,968,374)		×			
	AS	08-041309	02/1996	Japan (w/ English abstract and computer translation)	x				
	AT	08-081777	03/26/1996	Japan (w/ English abstract and computer translation)	·×				
	AU	08-268751	10/15/1996	Japan (w/ English abstract and computer translation)	×				
	AV	07-226378	08/22/1995	Japan (w/ English abstract and computer translation)	×				
	AW	64-039728	02/1989	Japan (w/ certified English translation)	×	L.			
	AX	03-115535	05/1991	Japan (w/ certified English translation)	×				
_	AY	05-117064	05/1993	Japan (w/ English abstract and corresponding to EP 0 508 731 filed		×			
			09/1993	herewith)  Japan (w/ English abstract and computer translation)	×	Ή			
	AZ	05-238859	03/1994	Japan (w/ English abstract and computer translation)	×				
	BA	06-057396	<del></del>	Japan (w/ English abstract and computer translation)	×				
	BB	06-136505	05/1994	Japan (w/ English abstract and computer translation)	×	1			
	BC	06-142822	05/1994	Japan (w/ English abstract and computer translation)	x	<del>                                     </del>			
	BD	07-126827	05/1995	Japan (w/ English abstract and computer translation)	x	1			
	BE	07-176524	07/1995	Japan (w/ English abstract and computer translation)	+	T			
	BF	08-037180	02/1996	Japan (w/ English abstract and computer variances)  Japan (w/ English abstract; corresponding to US Patent 5,919;332)	1	×			
	BG	08-339895	12/1996	Japan (w/ English abstract; corresponding to US Patent 5,909,354)	<del>                                     </del>	x			
·	ВН	09-069554	03/1997	Japan (w/ English abstract; corresponding to US Patent 5,955,182)		×			
VY	BI	09-272987	10/1997	Japan (w/ English abstract, corresponding to 05 Paterit 3,853,102)					
				Additional References sheet	s) attached	1			
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DOCUMENT NUMBER	DATE	COUNTRY	YES NO				
10-045461	02/1998	Japan (w/ English abstract and computer translation)	×				
10-045467	02/1998	Japan (w/ English abstract and computer translation)	×				
11-080925	03/1999	Japan (w/ English abstract; corresponding to US Patent 6,139,983)		х			
	08/1999	Japan (w/ English abstract and computer translation)	×				
	02/2001	Japan (w/ English abstract and computer translation)	×				
	09/1998	Japan (w/ English abstract; corresponding to US Patent 6,120,640)		×			
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-	06/19/2001	Japan (w/ computer translation; English abstract; corresponding to US					
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	08/1992	Great Britain	x	-			
06-256926	09/1994	Japan (w/ English abstract and computer translation)	<del></del>	-			
	10/1997	Europe (In English)					
10/2004- 0007601	01/2004	Korea (corresponding to US 2004/0168640A1)		├			
61-207566	09/1986	Japan (corresponding to US 5,204,189)		├—			
07-058013 A	03/1995	Japan (English abstract and computer translation)	<del>×</del>				
02-267967	11/1990	Japan (Certified translation filed herewith)	×	-			
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2004/030012	04/2004	WIPO		<u> </u>			
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2004/030015	04/2004	WIPO					
2004/030020	04/2004	WIPO		_			
2004/030426	04/2004	WIPO .					
2004/095530	11/2004	WIPO					
2004/095532	11/2004	WIPO					
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LIST OF REA	FEREN	NCES CITED BY	APPLICANT	Gary ESCHER, et al.			
				FILING DATE	GROUP		
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			U.S. P	ATENT DOCUMENTS			
EXAMINER		DOCUMENT	DATE	NAME	CLASS	SUB CLASS	
INITIAL VY	AA	NUMBER 6,176,969	01/23/2001	Park et al.		<b>.</b>	00.33
<del>'i</del>	AB	5,919,332	07/06/1999	Koshiishi et al.		1	
<b> </b>	AC		02/26/2004	Tomoyoshi et al.	<del></del>	+	
	_		11-1994	Robertson et al.		<del>                                     </del>	
	AD	5,366,585	<del></del>			<del>                                     </del>	
	AE	5,868,848	02-1999	Tsukamoto, Yuji		<del>                                     </del>	
	AF	6,110,287	08-2000	Arai et al.	<del>-</del>	<del>    -   -   -   -   -   -   -   -   -  </del>	
<u> </u>	AG	6,129,808	10-2000	Wicker et al.	·····		
	AH	6,264,788	07-2001	Tomoyasu et al.	<del></del>	<del></del>	
	Al	6,394,026	05-2002	Wicker et al.		<del>                                     </del>	
	AJ.	6,444,083	09-2002	Steger et al.		1	<u> </u>
	AK	6,514,377	02-2003	Morimoto, Tamotsu		<del>                                     </del>	
	AL	6,527,911	03-2003	Yen et al.		<del> </del>	
	AM	6,533,910	03-2003	O'Donnell et al.		<del>                                     </del>	
	AN	6,537,429	03-2003	O'Donnell et al.		ļ	· · · · · ·
	AO	6,544,380	04-2003	Tomoyasu et al.		<u> </u>	<b>}</b>
	AP	6,583,064	06-2003	Wicker et al.		ļ	<b>\</b>
	AQ	6,733,620	05-2001	Sugiyama et al.	<del></del> _	<u> </u>	H
	AR	2002/0086501	07-2002	O'Donnell et al.		-	<del>                                     </del>
	-AS-	-2002/0086545-	07-2002 -	O:Donnell.et.al	<del></del>		1
	AT	2002/0086553	07-2002.	O'Donnell et al.			$\sqcup$
	AU	2002/0142611	10-2002	O'Donnell et al.		ļ	<del>                                     </del>
	AV	2003/0084848	05-2003	Long, Maolin		<u> </u>	
	AW	2004/0026372	02-2004	Takenaka et al.		<u> </u>	
	AX	2004/0060516	04-2004	Nishimoto et al.			
	AY	2004/0060656	04-2004	Saigusa et al.			1
	AZ	2004/0060657	04-2004	Salgusa et al.		<u> </u>	
	ВА	2004/0060658	04-2004	Nishimoto et al.			
	вв	2004/0060661	04-2004	Nishimoto et al.			
	вс	2004/0061447	04-2004	Saigusa et al.	· · · · · · · · · · · · · · · · · · ·		
	BD	2004/0063333	04-2004	Saigusa et al.			
VY	BE	2004/0125359	07-2004	Ludviksson et al.			
	BF :				Additional References s	heet(s) atta	ched
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB	FILING DATE IF APPROPRIATE
VY	AA	6,894,769	05/2005	Ludviksson et al.	<b>\</b>		
	AB	6,875,477	04/2005	Trickett et al.	7		
	AC	6,852,433	02/2005	Maeda, Takao			
	AD	6,833,279	12/2004	Chol, Jin-Sik			
	AE	6,811,651	1 1/2004	Long, Maolin			
	AF	6,806,949	10/2004	Ludviksson et al.			
	AG	6,805,952	10/2004	Chang et al.		<u> </u>	
	АН	6,783,875	08/2004	Yamada et al.			
	Al	6,776,873	08/2004	Sun et al.			
	AJ	6,613,442	09/2003	O'Donnell et al.			
	AK	4,877,757	10/1989	York et al.			
	AL	5,637,237	06/1997	Oehrlein et al.			
	AM	5,834,070	11/1998	Movchan et al.			
	AN	6,296,740	10/2001	Xie et al.			
	AO	6,613,204	09/2003	Xie et al.			
	AP	5,891,253	04/1999	Wong et al.			
	AQ	2004/0050495	03/2004	Sumiya et al.			
	AR	2004/0083970	05/2004	Imafuku et al.			
-	AS	5,885,356	03/1999	Zhao et al.			
	AT	2001/0050144	12/2001	Nishikawa et al.			
	AU	5,902,763	05/1999	Waku et al.			
	AV	5,423,936	06/1995	Tomita et al.			
	AW	6,554,906	04/2003	Kuibira, et al.			
	AX	6,266,133	07/2001	Miyajima, et al.			
VY	AY	2004/0168640A1	09/2004	Muto, et al.			\
		OTHER R	EFERENCES	(Including Author, Title, Date, Pertinen	t Pages, e	tc.)	
VY	AZ	Production drawin	g for Depos	ition Shield, Upper believed to be	sold in	the U.S.	on April 12, 2000.
VY	ВА	Production drawin 2001.	g for Depos	ition Shield believed to be sold in	the U.S	. prior to	September 30,
VY	BB.	Production drawin	g for Upper	Electrode believed to be sold in t	the U.S.	prior to	September 30, 2001.
VY	вс	JIS Using Series, Association), with	Spraying T	echniques Manual.", p. 95 (Oct. 3	30, 1998	, Japane	se Standard
					Add	ditional Re	ferences sheet(s) attached
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EXAMINER DOCUMENT DATE NUMBER		NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE				
VY	AA	4,842,683	06/1989	Cheng et al.			·		
	AB	6,663,714	12/203	Mizuno et al.			1		
	AC	6,726,801	04/2004	Ahn, Jae-Su					
	AD	6,562,186	05-2003	Saito et al.	156	345.24			
	AE	5,885,402	03-1999	Esquibel, James	156	345.24			
	AF	2002/0177001	11-2002	Harada et al.	428	469			
	AG	5,521,790	05-1996	Ruckel et al.	361	234			
	AH	6,068,729	05-2000	Shrotriya, Ashish V.	156	345.26			
	AI	5,968,377	10-1999	Yuasa et al.					
	AJ	5,955,182	09/1999	Yasuda et al.					
	AK	6,364,949	4/2002	Or et al.					
	AL	5,911,852	6/1999	Katayama et al.					
	AM	5,074,456	12/1991	Degner et al.					
	AN	4,612,077	9/1986	Tracy et al.					
	AO	6,182,603	2/2001	Shang et al.			·		
	AP	2003/0010446	1/2003	Kajiyama et al.					
	AQ	2001/0003271	6/2001	Otsuki					
	AR	2002/0076508	6/2002	Chiang et al.					
	AS	6,368,987	4/2002	Kopacz et al.					
	AT	2004/0072426	4/2004	Jung					
	AU	2005/0150866	07-2005	O'Donnell	216	067			
	AV	2003/0113479	06-2003	Fakuda et al.	427	569			
	AW	4,357,387	11-1982	George et al.	442	71			
	AX	5,925,228	07-1999	Panitz	204	484	<del></del>		
	AY	5,892,278	07-1999	Horita	257	706			
	AZ	6,073,449	06-2000	Watanabe et al.	62	3.2			
	ВА	2005/0103275	02-2004	Sasaki et al.					
VY	88	4,310,390	01-1982	Bradley et al.		<u> </u>			
					Ad	ditional Ref	erences sheet(s) attach		
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
VY	AA	6,383,964	5/2002	Nakahara et al.	-	02.00		
<del>- i</del>	AB	6,123,791	9/2000	Han et al.	1			
	AC	6,170,429	1/2001	Schoepp et al.	1	-		
	AD	6,096,161	8/2000	Kim et al.				
	AE	5,362,335	11/1994	Rungta				
	AF	5,952,060	9/1999	Ravi	-			
	AG	5,680,013	10/1997	Domfest et al.	<del>                                     </del>			
		5,494,713	2/1996	Ootuki	+			
	AH		3/1991	Wang et al.	<del>- </del>	<del>                                     </del>	-	
	AJ AK	5,000,113 5,334,462	8/1994	Vine et al.	+			
	AL	6,830,622	12/2004	O'Donnell et al.	+	+		
	AM	6,335,293	1/2002	Luo et al.	+	+		
		6.221,202	4/2001	Walko, II		$\vdash$	<del></del>	
	AN		5/1999	Kholodenko	<del></del>	-		
	AO	5,900,064	6/1997	Nitescu et al.			<del></del>	
-+	AP	5,641,375 6,383,333	5/2002	Haino et al.		<del>                                     </del>		
			7/2003	Jung et al.	-	<del>\</del>		
-	AR	6,590,660	5/2003	Jung et al.			<del>                                     </del>	
	AS	6,570,654	2/2003	Jung et al.	_		<del>                                     </del>	
	AU	6,373,573	4/2002	Jung et al.		<del>                                     </del>		
	AV	6,246,479	6/2001	Jung et al.	_			
	AW	5,851,343	12/1998	Hsu et al.				
	AX	6,210,486	4/2001	Mizukami et al.	<del> </del>		1	
_	AY	2002/0086118	7/2002	Chang et al.	-			
	AZ	2003/0029563	2/2003	Kaushal et al.	_			
	BA	4,593,007	6/1986	Novinski	<del></del>			
	BB	5,985,102	11/1999	Leiphart	_		• 1	
	BC	6,106,625	8/2000	Koal et al.	· ·	<u> </u>	<del>                                     </del>	
	BD	6,123,804	9/2000	Babassi et al.			<u> </u>	
	BE	6,265,757	7/2001	Brady et al.			1	
	BF	6,143,646	11/2000	Wetzel	<del>- </del>	1	<del>\</del>	
<del>-   -</del>	BG	2002/0090464	7/2002	Jiang et al.		<b> </b>	<del>                                     </del>	
	ВН	4,469,619	9/1984	Ohno et al.	_	<del> </del>	<b>—</b>	
<del> </del>	Ві	5,426,310	6/1995	Tamada et al.	<del>                                     </del>		<del>                                     </del>	
	BJ	5,556,501	9/1996	Collins et al.			<b>\</b>	
	ВК	5,614,055	3/1997	Fairbairn et al.		<del>                                     </del>		
	BL	5,944,902	8/1999	Redeker et al.		<b>†</b>		
VY	ВМ	5,994,662	11/1999	Murugesh		<del> </del>		
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VY		AA	5,894,887	4/1999	Kelsey et al.	1						
		AB	5,879,575	3/1999	Tepman et al.							
		AC	5,759,360	6/1998	Ngan et al.							
		AD	5,798,016	8/1998	Oehrlein et al.							
		AE	6,139,983	10/2000	Ohashi et al.							
		AF	5,484,752	1/1996	Waku et al.		<b>\</b>					
		AG	5,895,586	4/1999	Kaji et al.							
		АН	6,120,640	9/2000	Shih et al.							
		Al	6,738,862	5/2004	Ross et al.							
		AJ	6,783,863	8/2004	Harada et al.			·				
		AK	6,837,966	1/2005	Nishimoto et al.							
		AL	6,798,519	9/2004	Nishimoto et al.							
		AM	2004/0173155	9/2004	Nishimoto et al.							
		AN	6,641,697	11/2003	Han et al.							
		AO	2004/0081746	4/2004	Imafuku							
		AP	2003/0200929	10/2003	Otsuki-							
		AQ	6,884,516	4/2005	Harada et al.							
		AR	6,695,929	2/2004	Kanekiyo et al.							
		AS	5,725,960	3/1998	Konishi et al.							
		AT	5,551,190	9/1996	Yamagishi et al.							
		AU	2005/0103268	5/2005	Nishimoto et al.							
V	Y	AV	2004/0216667	11/2004	Mitsuhashi et al.							
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